

FIG. 1A

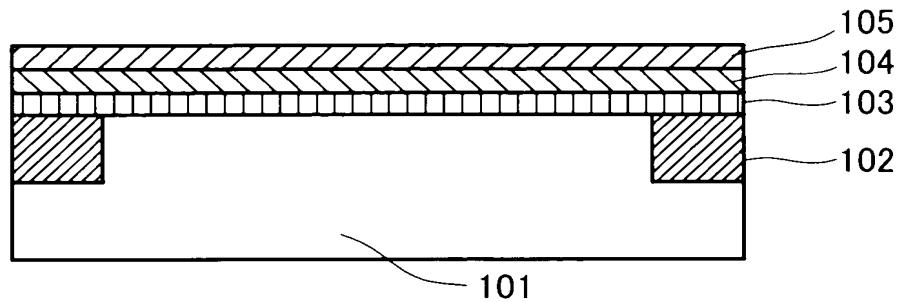


FIG. 1B

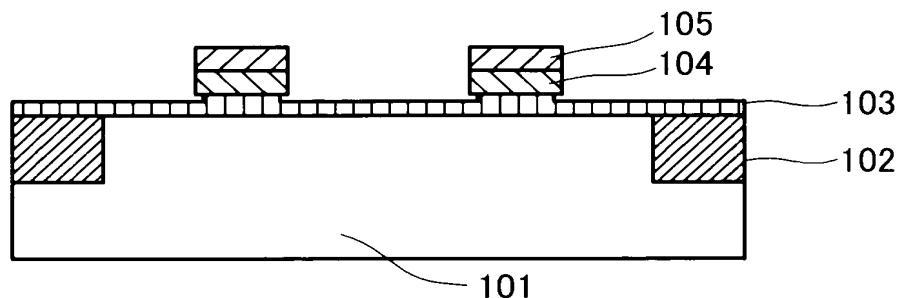


FIG. 1C

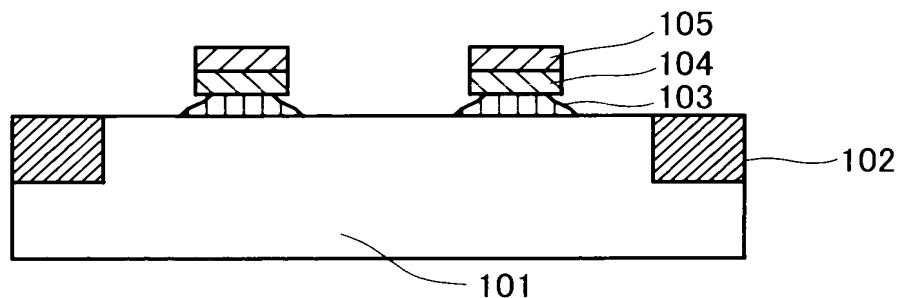


FIG. 1D

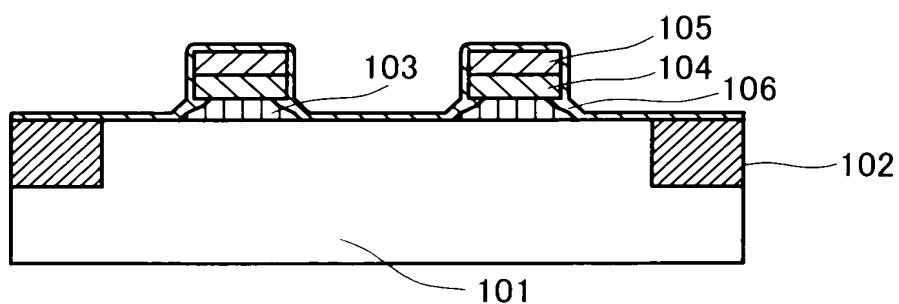


FIG. 2A

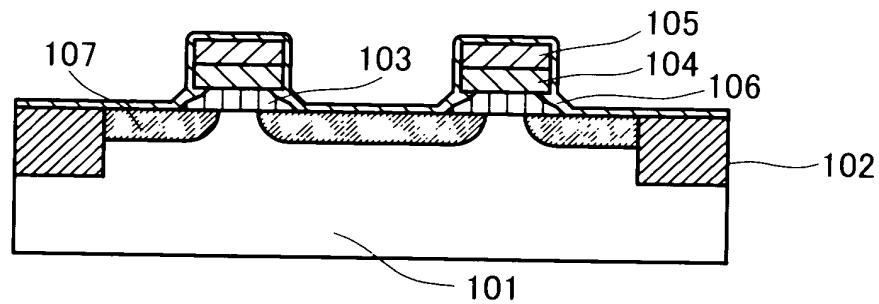


FIG. 2B

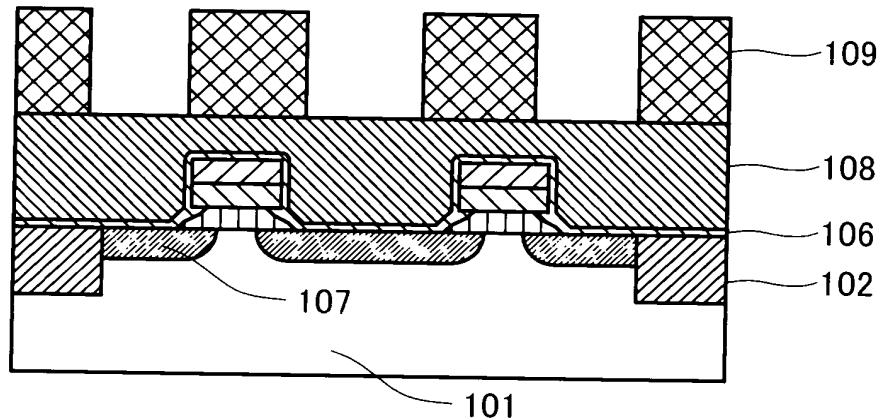


FIG. 2C

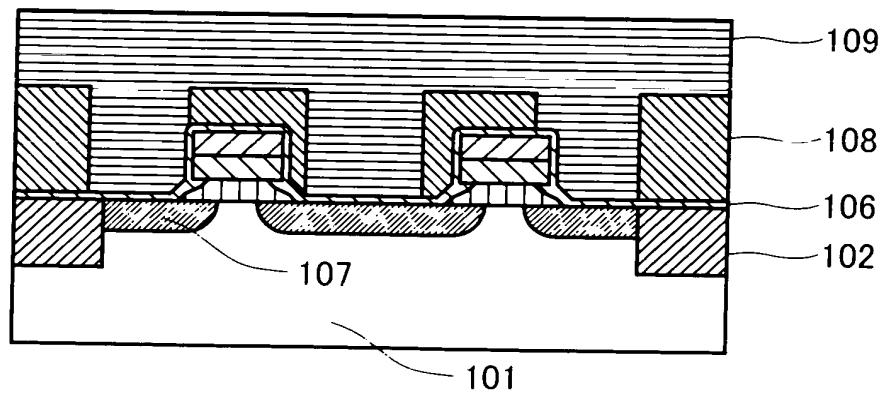


FIG. 3A

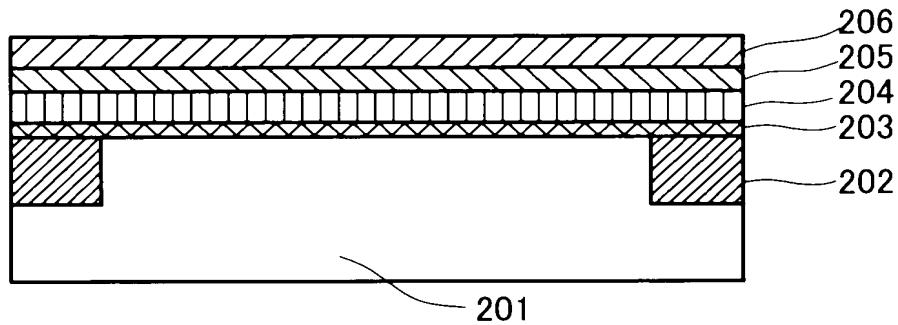


FIG. 3B

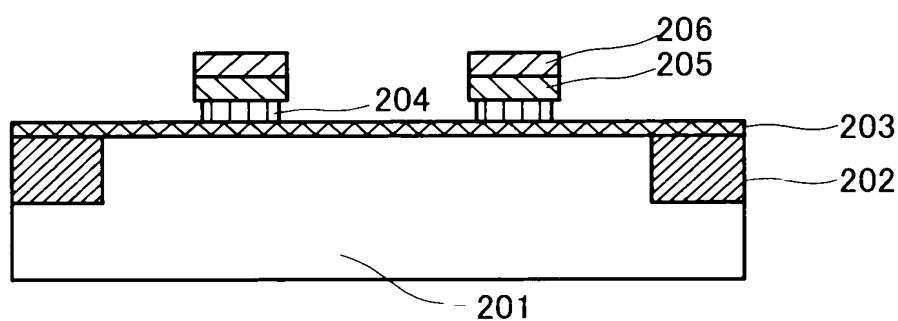


FIG. 3C

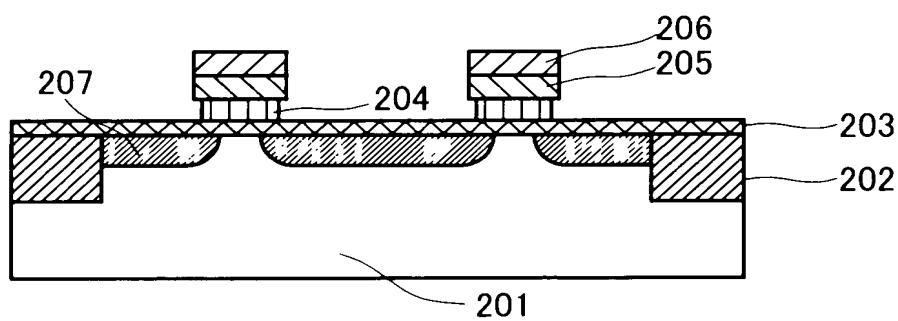


FIG. 4A

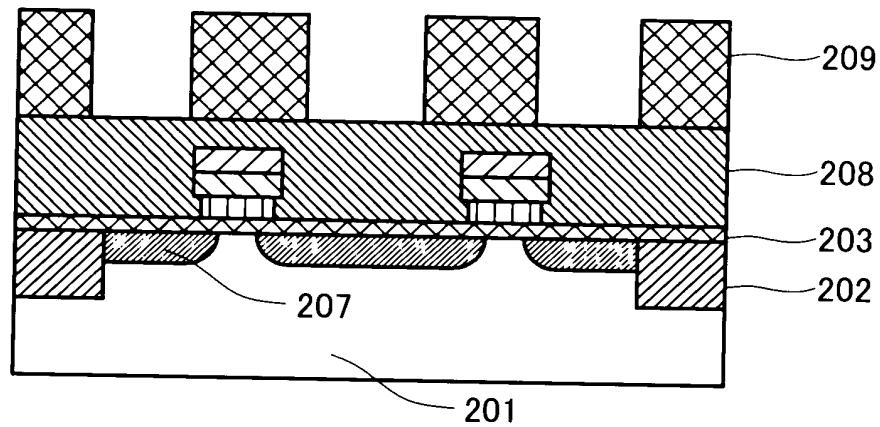


FIG. 4B

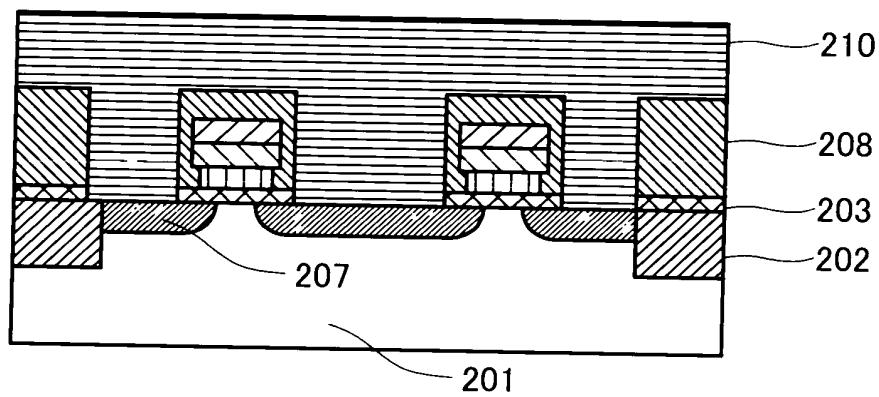
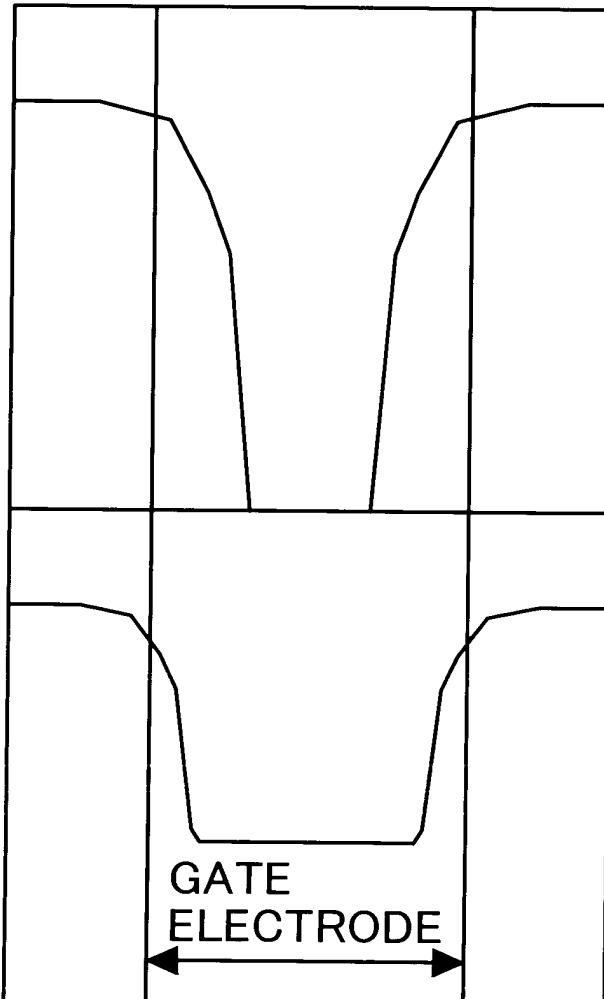


FIG. 5

EQUIVALENT SiO_2
THICKNESS OF GATE
INSULATING FILM

IMPURITY CONCENTRATION
IN SOURCE/DRAIN



POSITION OF
CHANNEL DIRECTION

FIG. 6A

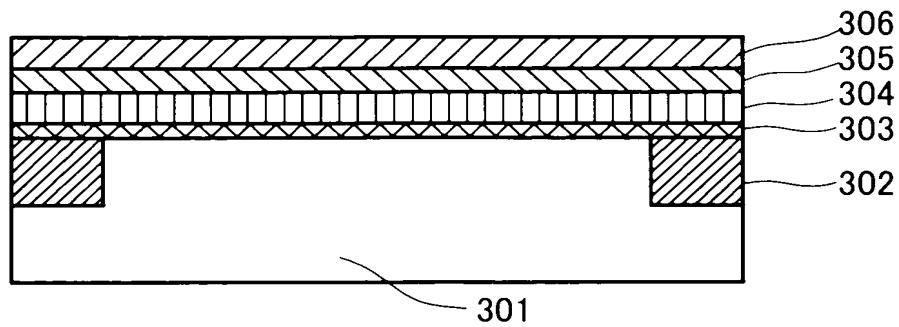


FIG. 6B

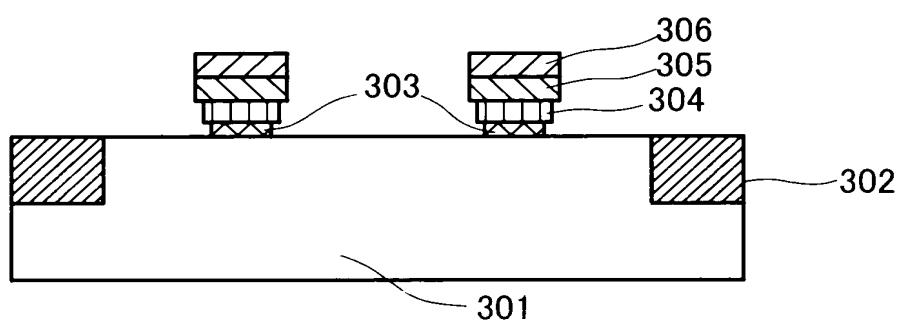


FIG. 6C

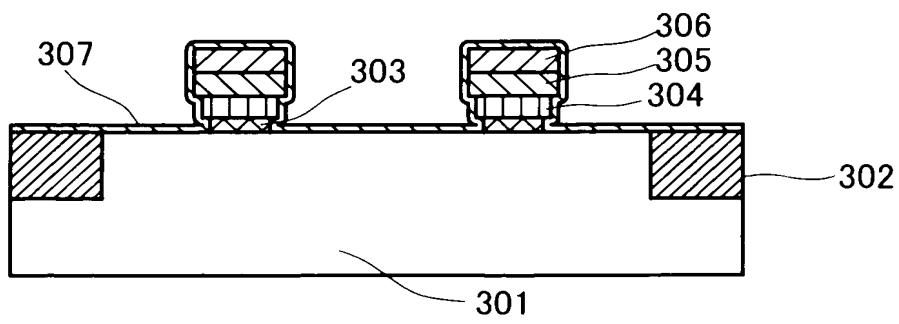


FIG. 7A

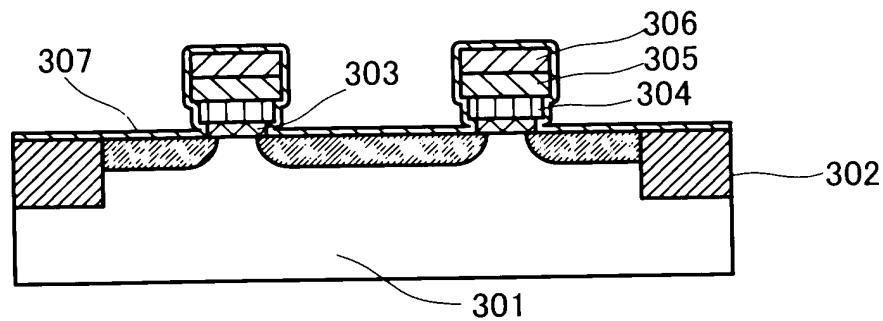


FIG. 7B

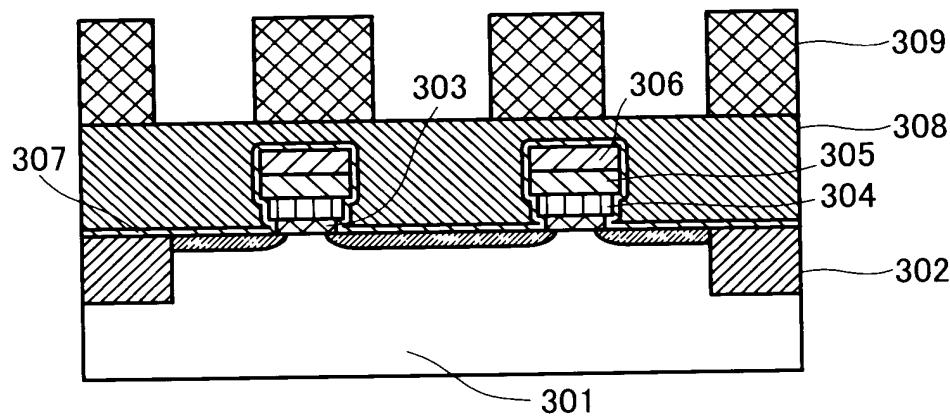


FIG. 7C

